

FDP12N60NZ / FDPF12N60NZ N-Channel MOSFET 600V, 12A, 0.65Ω

Features

- $R_{DS(on)} = 0.53\Omega$ (Typ.)@ $V_{GS} = 10V$, $I_D = 6A$
- Low gate charge (Typ. 26nC)
- Low C_{rss} (Typ. 12pF)
- · Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- ESD Improved capability
- RoHS compliant

Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DOMS technology.

September 2010

UniFET-II[™]

This advance technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutationmode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.



MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

Symbol	Parameter			FDP12N60NZ	FDPF12N60NZ	Units	
V _{DSS}	Drain to Source Voltage			600		V	
V _{GSS}	Gate to Source Voltage			±30		V	
ID	Drain Current	-Continuous ($T_C = 25^{\circ}C$)		12	12*	•	
		-Continuous ($T_c = 100^{\circ}C$)		7.2	7.2*	A	
I _{DM}	Drain Current	Drain Current - Pulsed (Note 1)		48	48*	Α	
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)) 565		mJ	
I _{AR}	Avalanche Current		(Note 1)	12		Α	
E _{AR}	Repetitive Avalanche Energy		(Note 1)	24		mJ	
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	10		V/ns	
P _D	Power Dissipation	$(T_{C} = 25^{\circ}C)$		240	39	W	
		- Derate above 25°C		2.0	0.3	W/ºC	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150		°C		
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300		°C	

Symbol	Parameter	FDP12N60NZ	FDPF12N60NZ	Units
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	0.52	3.2	
$R_{\theta CS}$	Thermal Resistance, Case to Sink Typ.	0.5	-	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	62.5	

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Device Marking Device		Device	Packag	je	Reel Size	Таре	e Width		Quantit	у
FDP12N60NZ FDP12N60NZ		TO-220	0	-		-		50		
FDPF12N	60NZ	FDPF12N60NZ	TO-220	F	-		-		50	
Electrica	l Char	acteristics								
Symbol		Parameter		Test Conditions		Min.	Тур.	Max.	Units	
Off Charac	teristic	S								
BV _{DSS}	Drain to	o Source Breakdown V	oltage	$I_D = 250\mu A, V_{GS} = 0V, T_J = 25^{o}C$		600	-	-	V	
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$		Breakdown Voltage Temperature		$I_D = 250\mu A$, Referenced to $25^{\circ}C$		-	0.6	-	V/ºC	
 	Zero G	Zero Gate Voltage Drain Current			V, $V_{GS} = 0V$		-	-	1	μA
IDSS	Zeiu G	ale vollage Dialit Cult	ent		V, $T_{C} = 125^{\circ}C$		-	-	10	μА
I _{GSS}	Gate to	Body Leakage Currer	nt	$V_{GS} = \pm 30$	V, $V_{DS} = 0V$		-	-	±10	μA
On Charac	teristic	S								
V _{GS(th)}	Gate T	hreshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$		3	-	5	V		
R _{DS(on)}	Static E	Drain to Source On Res	sistance	V _{GS} = 10\	/, I _D = 6A		-	0.53	0.65	Ω
9 _{FS}	Forwar	Forward Transconductance			′, I _D = 6A	(Note 4)	-	13.5	-	S
Dynamic C	haract	eristics								
C _{iss}	Input Capacitance						-	1260	1676	pF
C _{oss}	Output	tput Capacitance verse Transfer Capacitance		- V _{DS} = 25V, V _{GS} = 0V - f = 1MHz		-	150	200	pF	
C _{rss}	Revers					-	12	18	pF	
Q _{g(tot)}	Total G	otal Gate Charge at 10V Gate to Source Gate Charge Gate to Drain "Miller" Charge		$V_{DS} = 480V, I_D = 12A$ $V_{GS} = 10V$ (Note 4, 5)		-	26	34	nC	
Q _{gs}	Gate to					-	6	-	nC	
Q _{gd}	Gate to					(Note 4, 5)	-	10	-	nC
Switching	Charac	teristics		-						
t _{d(on)}	1	n Delay Time					-	25	60	ns
t _r	Turn-O	On Rise Time		V _{DD} = 300V, I _D = 12A		-	50	110	ns	
t _{d(off)}	Turn-O	ff Delay Time		$R_{G} = 25\Omega$		-	80	170	ns	
t _f	Turn-O	n-Off Fall Time		(Note 4, 5)		-	60	130	ns	
Drain-Sou	ce Dio	de Characteristic	S							
I _S	Maximum Continuous Drain to Source Diode Forward Current						-	-	12	Α
I _{SM}	Maximum Pulsed Drain to Source Diode For			rward Current		-	-	48	Α	
V _{SD}	Drain to	Source Diode Forwar	d Voltage	$V_{GS} = 0V, I_{SD} = 12A$		-	-	1.4	V	
t _{rr}	Reverse	e Recovery Time	-	$V_{GS} = 0V,$			-	350	-	ns
Q _{rr}	-	everse Recovery Charge		-100 = 00,	$I_{\rm F}/dt = 100 A/\mu s$ (Note 4)		-	2.2		μC

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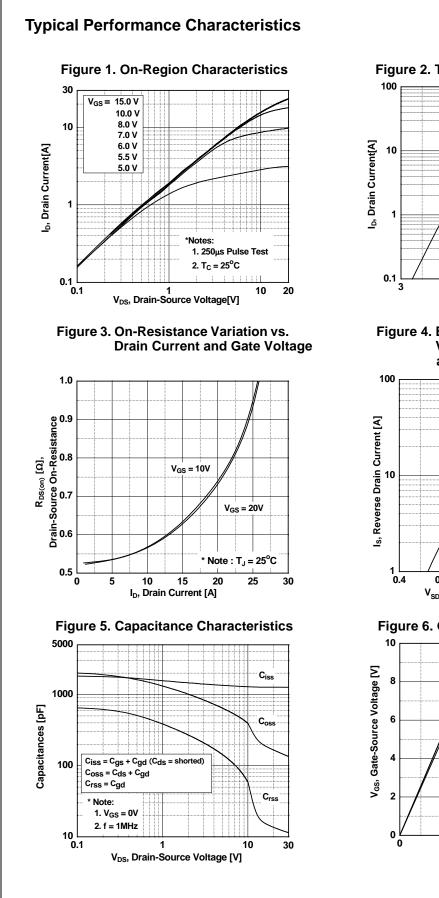
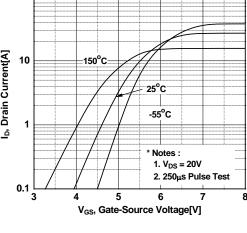
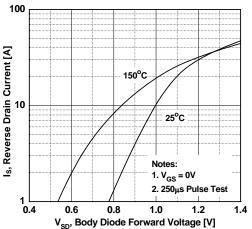


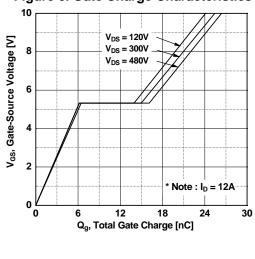
Figure 2. Transfer Characteristics

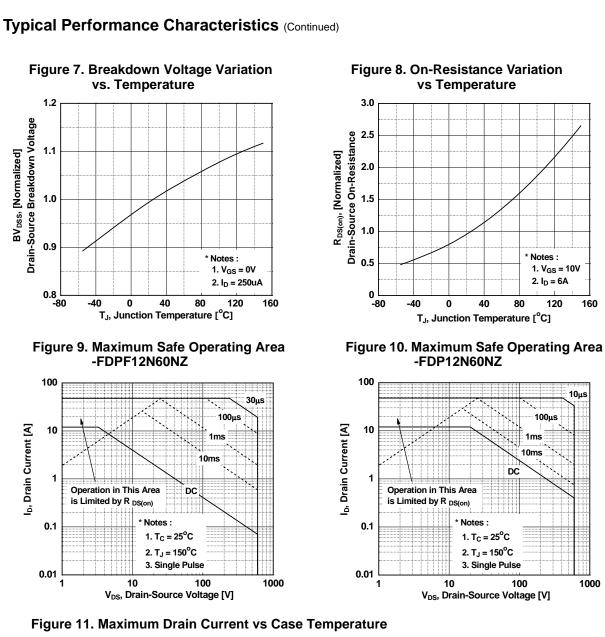


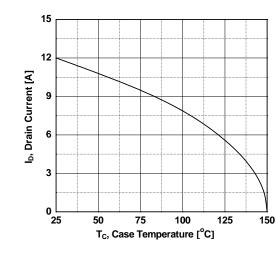












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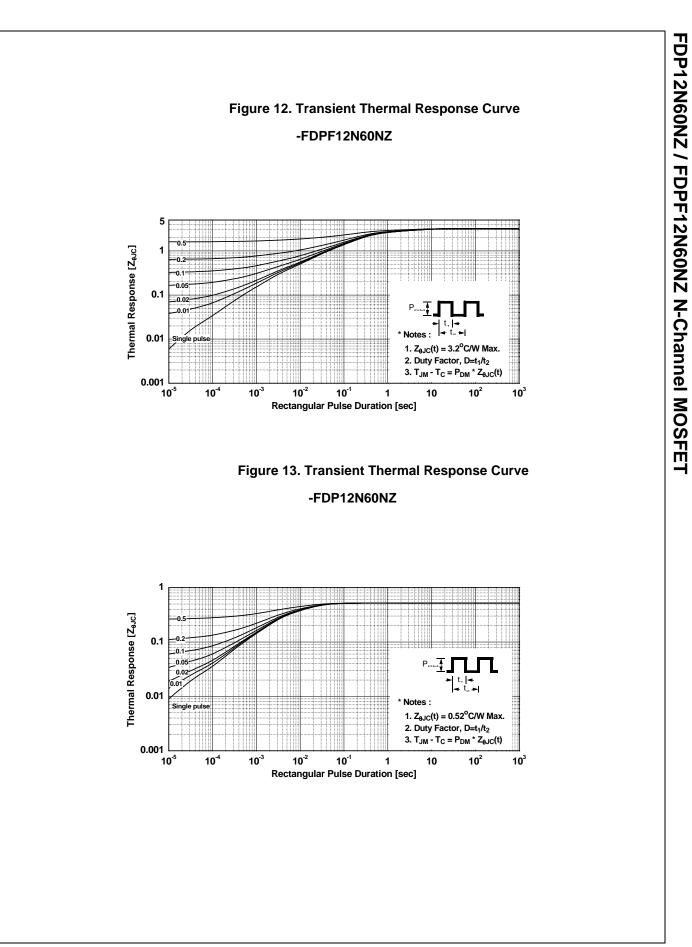
Drain-Source Breakdown Voltage

I_D, Drain Current [A]

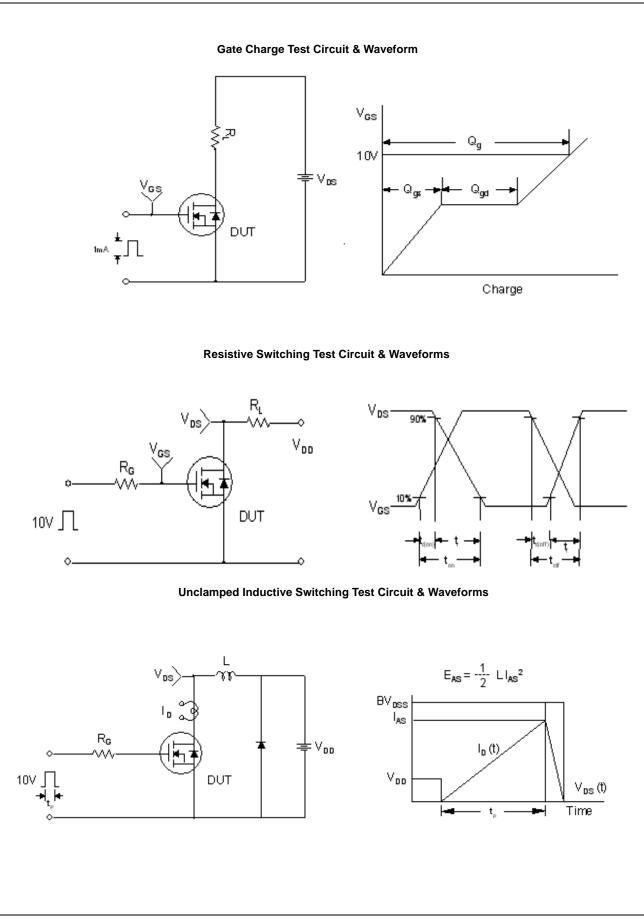
BV_{DSS}, [Normalized]

1.1

4



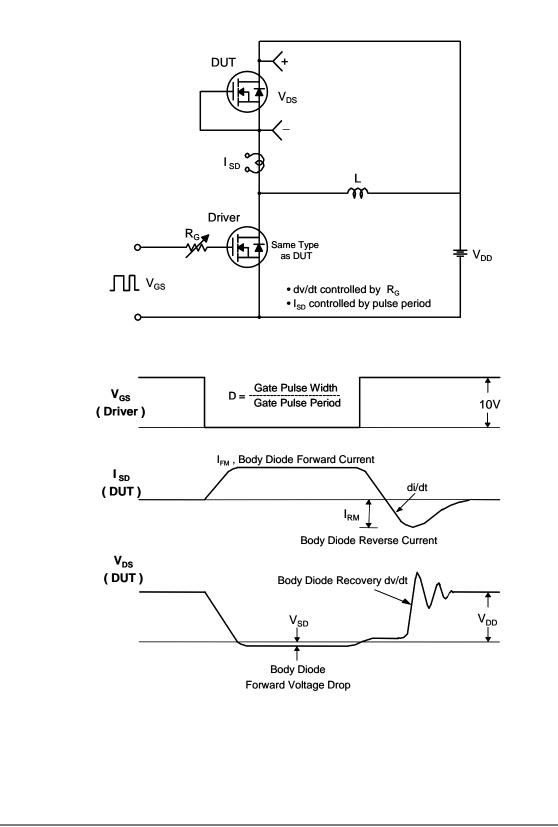
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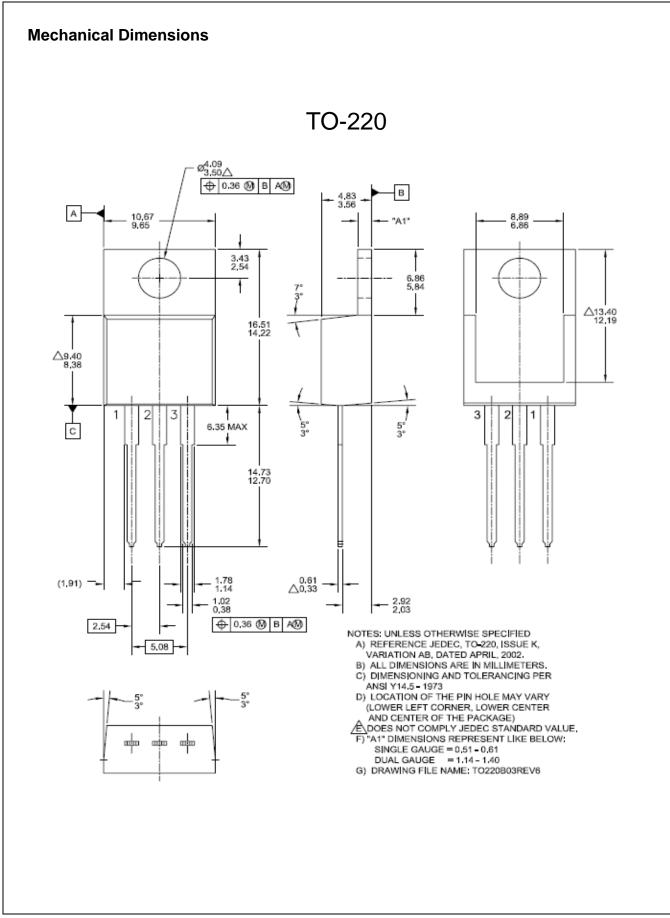
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Peak Diode Recovery dv/dt Test Circuit & Waveforms



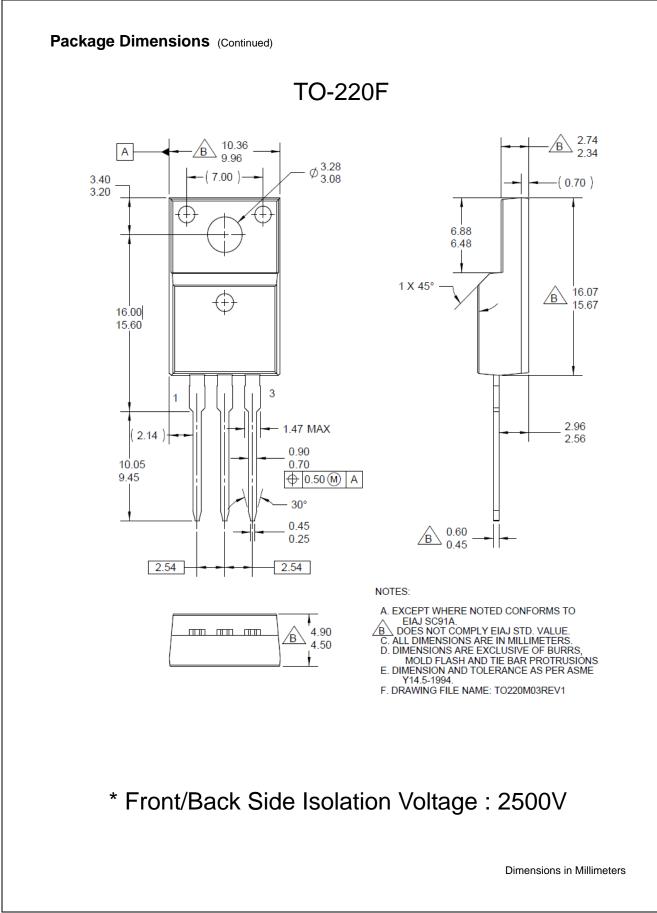
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